

RoHS Compliant Product  
A suffix of "-C" specifies halogen & lead-free

## DESCRIPTION

These miniature surface mount MOSFETs utilize high cell density process. Low R<sub>DS(on)</sub> assures minimal power loss and conserves energy, making this device ideal for use in power management circuitry.

## FEATURES

- Low R<sub>DS(on)</sub> provides higher efficiency and extends battery life.
- Miniature SOP-8 surface mount package saves board space.
- High power and current handling capability.

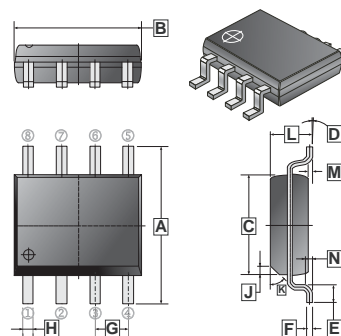
## APPLICATION

PWMDC-DC converters, power management in portable and battery-powered products such as computers, printers, battery charger, telecommunication power system, and telephones power system.

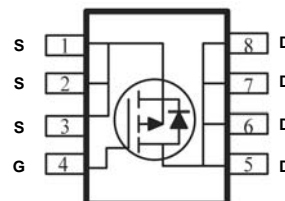
## PACKAGE INFORMATION

Package	MPQ	Leader Size
SOP-8	2.5K	13' inch

### SOP-8



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	5.80	6.20	H	0.35	0.49
B	4.80	5.00	J	0.375	REF.
C	3.80	4.00	K	45°	
D	0°	8°	L	1.35	1.75
E	0.40	0.90	M	0.10	0.25
F	0.19	0.25	N	0.25	REF.
G	1.27	TYP.			



## MAXIMUM RATINGS (T<sub>A</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V <sub>DS</sub>	-20	V
Gate-Source Voltage	V <sub>GS</sub>	±12	V
Continuous Drain Current <sup>1</sup>	I <sub>D</sub>	T <sub>A</sub> = 25°C	-13.4
		T <sub>A</sub> = 70°C	-8.4
Pulsed Drain Current <sup>2</sup>	I <sub>DM</sub>	±50	A
Continuous Source Current (Diode Conduction) <sup>1</sup>	I <sub>S</sub>	-2.1	A
Total Power Dissipation <sup>1</sup>	P <sub>D</sub>	T <sub>A</sub> = 25°C	3.1
		T <sub>A</sub> = 70°C	2.0
Operating Junction & Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 ~ 150	°C
<b>Thermal Resistance Rating</b>			
Thermal Resistance Junction-Case (Max.) <sup>1</sup>	t ≤ 5 sec	R <sub>θJC</sub>	25
Thermal Resistance Junction-Ambient (Max.) <sup>1</sup>	t ≤ 5 sec	R <sub>θJA</sub>	40

Notes:

1. Surface Mounted on 1" x 1" FR4 Board.
2. Pulse width limited by maximum junction temperature.

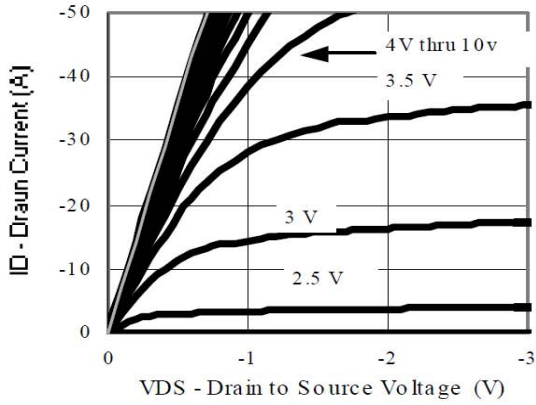
**ELECTRICAL CHARACTERISTICS** (T<sub>A</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
<b>Static</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	-0.7	-	-	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = -250μA
Gate-Body Leakage	I <sub>GSS</sub>	-	-	±100	nA	V <sub>DS</sub> =0, V <sub>GS</sub> = ±12V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	-	-	-1	μA	V <sub>DS</sub> = -16V, V <sub>GS</sub> =0
		-	-	-5		V <sub>DS</sub> = -16V, V <sub>GS</sub> =0, T <sub>J</sub> =55°C
On-State Drain Current <sup>1</sup>	I <sub>D(on)</sub>	-50	-	-	A	V <sub>DS</sub> = -4.5V, V <sub>GS</sub> = -10V
Drain-Source On-Resistance <sup>1</sup>	R <sub>DS(ON)</sub>	-	-	11.5	mΩ	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -11.5A
		-	-	19		V <sub>GS</sub> = -2.5V, I <sub>D</sub> = -10.4A
		-	-	35		V <sub>GS</sub> = -1.8V, I <sub>D</sub> = -7.7A
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	-	70	-	S	V <sub>DS</sub> = -15V, I <sub>D</sub> = -11.5A
Diode Forward Voltage	V <sub>SD</sub>	-	-0.6	-	V	I <sub>S</sub> = -2.5A, V <sub>GS</sub> =0
<b>Dynamic <sup>2</sup></b>						
Total Gate Charge	Q <sub>g</sub>	-	33.4	-	nC	I <sub>D</sub> = -11.5A V <sub>DS</sub> = -10V V <sub>GS</sub> = -4.5V
Gate-Source Charge	Q <sub>gs</sub>	-	5.9	-		
Gate-Drain Charge	Q <sub>gd</sub>	-	8.1	-		
Turn-On Delay Time	T <sub>d(on)</sub>	-	20	-	nS	V <sub>DD</sub> = -10V I <sub>D</sub> = -1A V <sub>GEN</sub> = -4.5V R <sub>L</sub> = 6Ω
Rise Time	T <sub>r</sub>	-	23	-		
Turn-Off Delay Time	T <sub>d(off)</sub>	-	289	-		
Fall Time	T <sub>f</sub>	-	134	-		

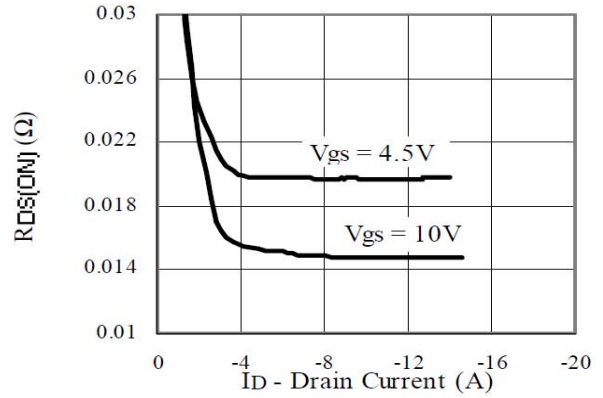
Notes:

1. Pulse test : PW ≤ 300μs duty cycle ≤ 2%.
2. Guaranteed by design, not subject to production testing.

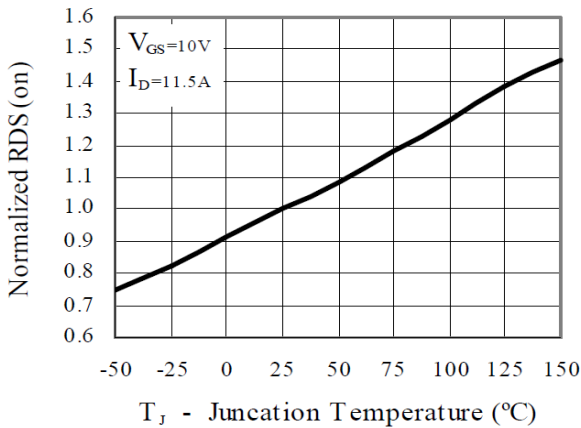
**CHARACTERISTIC CURVES**



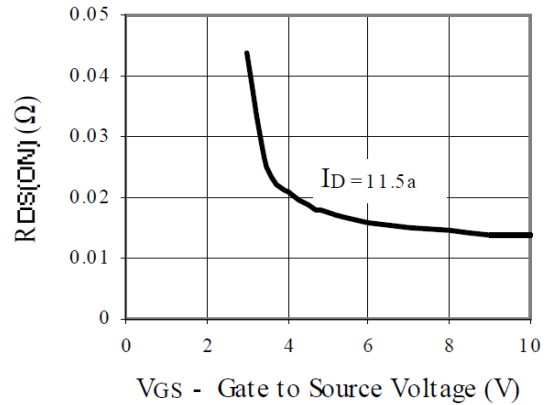
**Figure 1. On-Region Characteristics**



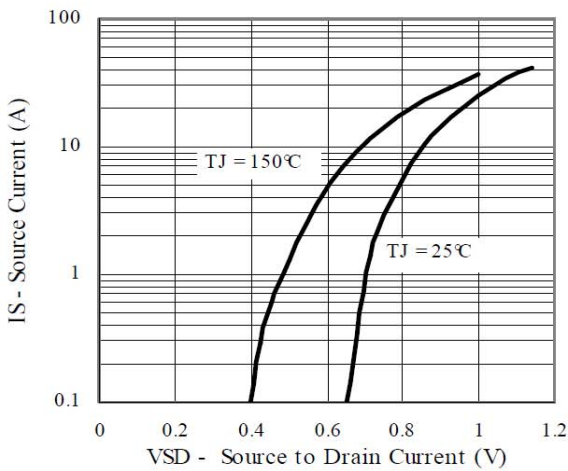
**Figure 2. On-Resistance Variation with Drain Current and Gate Voltage**



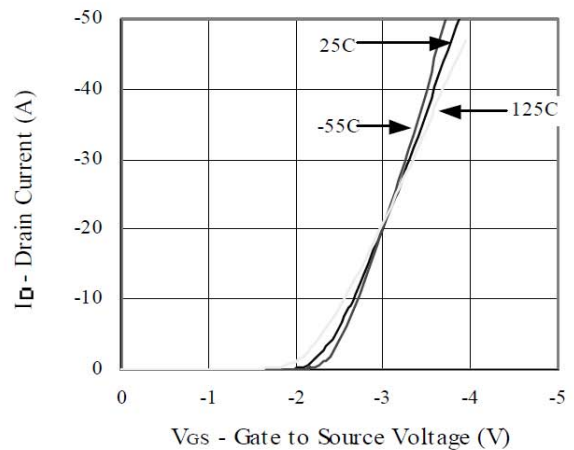
**Figure 3. On-Resistance Variation with Temperature**



**Figure 4. On-Resistance with Gate to Source Voltage**



**Figure 5. Transfer Characteristics**



**Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature**

**CHARACTERISTIC CURVES**

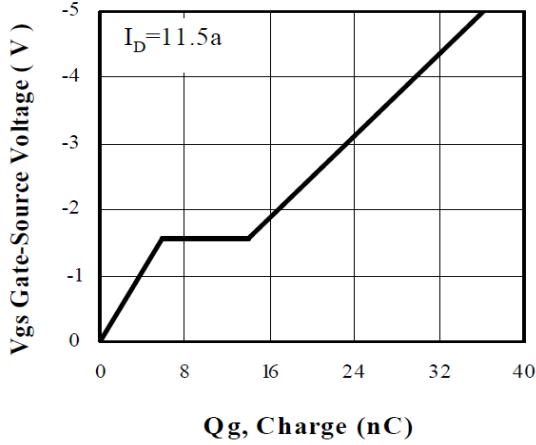


Figure 7. Gate Charge Characteristics

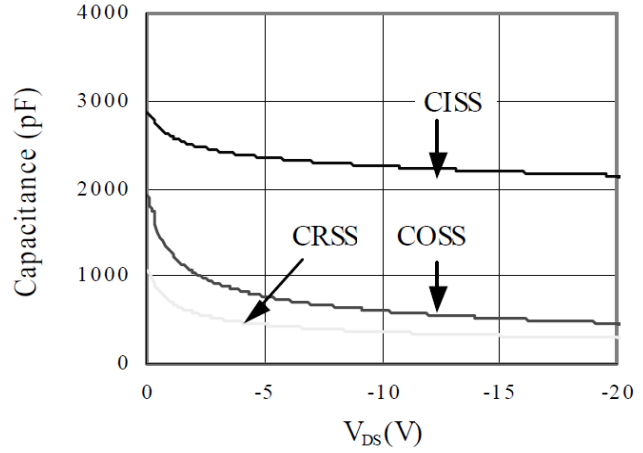


Figure 8. Capacitance Characteristics

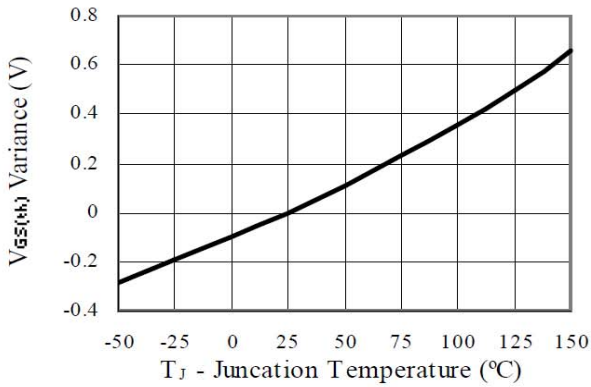


Figure 9. Maximum Safe Operating Area

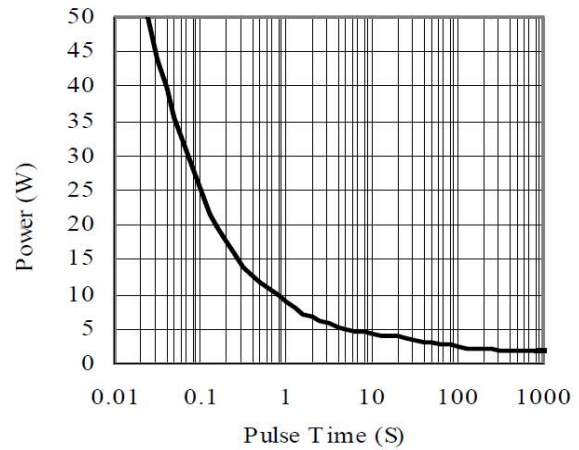


Figure 10. Single Pulse Maximum Power Dissipation

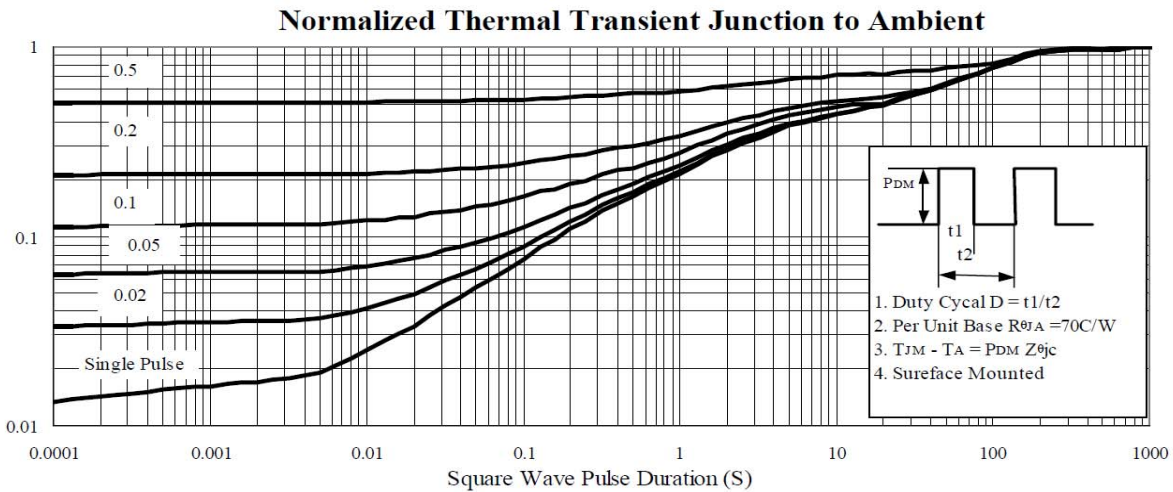


Figure 11. Transient Thermal Response Curve